SCBS727 - JULY 2000

 BiCMOS Technology With Low Quiescent Power 		CKAGE VIEW)
Buffered Inputs		
Noninverted Outputs	1D 🛛 2	23 🛛 1Q
 Input/Output Isolation From V_{CC} 	2D 🛛 3	22 2 2Q
Controlled Output Edge Rates	3D 🛛 4	21 3Q
• 48-mA Output Sink Current	4D [5	20 4Q
•	5D [6	19 5Q
 Output Voltage Swing Limited to 3.7 V 	6D 🛛 7	18 6Q
 SCR Latch-Up-Resistant BiCMOS Process 	7D 🛛 8	17 7Q
and Circuit Design	8D 🛛 9	16 🛛 8Q
 Packaged in Plastic Small-Outline Package 	9D 🛿 10	15 🛛 9Q
· ······	CLR [11	14] PRE
description	GND 12	13 LE

The CD74FCT843A is a 9-bit, bus-interface, D-type latch with 3-state outputs, designed

specifically for driving highly capacitive or relatively low-impedance loads. It is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The device uses a small-geometry BiCMOS technology. The output stage is a combination of bipolar and CMOS transistors that limits the output high level to two diode drops below V_{CC} . This resultant lowering of output swing (0 V to 3.7 V) reduces power-bus ringing [a source of electromagnetic interference (EMI)] and minimizes V_{CC} bounce and ground bounce and their effects during simultaneous output switching. The output configuration also enhances switching speed and is capable of sinking 48 mA.

The CD74FCT843A outputs are transparent to the inputs when the latch-enable (LE) input is high. The latches are transparent D-type latches. When LE goes low, the data is latched. The output-enable (\overline{OE}) input controls the 3-state outputs. When \overline{OE} is high, the outputs are in the high-impedance state. The latch operation is independent of the state of the output enable. This device, having preset (\overline{PRE}) and clear (\overline{CLR}), are ideal for parity-bus interfacing. When \overline{PRE} is low, the outputs are high if \overline{OE} is low. PRE overrides CLR. When \overline{CLR} is low, the outputs are low if \overline{OE} is low. When \overline{CLR} is high, data can be entered into the latch. The device provides noninverted outputs.

OE does not affect the internal operations of the latch. Previously stored data can be retained or new data can be entered while the outputs are in the high-impedance state.

The CD74FCT843A is characterized for operation from 0°C to 70°C.

	FUNCTION TABLE (each latch)									
	INPUTS									
PRE	CLR	OE	LE	D	Q					
L	Х	L	Х	Х	Н					
н	L	L	Х	Х	L					
н	н	L	Н	L	L					
н	н	L	Н	Н	н					
н	Н	L	L	Х	Q ₀ Z					
Х	Х	Н	Х	Х	Z					



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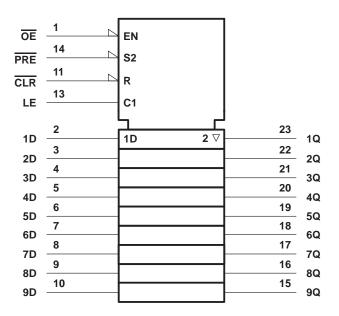
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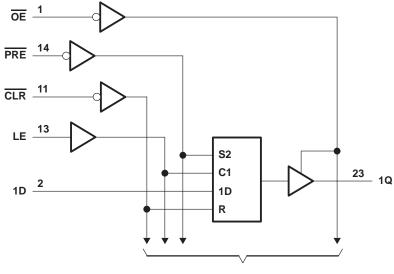
CD74FCT843A BiCMOS 9-BIT BUS-INTERFACE D-TYPE LATCH WITH 3-STATE OUTPUTS SCBS727 - JULY 2000

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Eight Other Channels



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

DC supply voltage range, V_{CC} DC input clamp current, I_{IK} ($V_I < -0.5 V$) DC output clamp current, I_{OK} ($V_O < -0.5 V$) DC output sink current per output pin, I_{OL} DC output source current per output pin, I_{OH} Continuous current through V_{CC} , (I_{CC}) Continuous current through GND Package thermal impedance, θ_{VA} (see Note 1)	
Package thermal impedance, θ_{JA} (see Note 1)	46°C/W

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 2)

		MIN	MAX	UNIT
VCC	Supply voltage	4.75	5.25	V
VIH	High-level input voltage	2		V
VIL	Low-level input voltage		0.8	V
VI	Input voltage	0	VCC	V
VO	Output voltage	0	VCC	V
ЮН	High-level output current		-15	mA
IOL	Low-level output current		48	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	10	ns/V
TA	Operating free-air temperature	0	70	°C

NOTE 2: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

electrical characteristics over recommended operating temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Vaa	T _A = 25°C	MIN	МАХ	UNIT
PARAMETER	TEST CONDITIONS	Vcc	MIN MAX		MAX	UNIT
VIK	$I_{I} = -18 \text{ mA}$	4.75 V	-1.2	2	-1.2	V
VOH	I _{OH} = -15 mA	4.75 V	2.4	2.4		V
V _{OL}	$I_{OL} = 48 \text{ mA}$	4.75 V	0.55	5	0.55	V
lı	$V_I = V_{CC}$ or GND	5.25 V	±0.1		±1	μA
I _{OZ}	$V_{O} = V_{CC} \text{ or } GND$	5.25 V	±0.8	5	±10	μA
los‡	$V_{I} = V_{CC} \text{ or } GND, \qquad V_{O} = 0$	5.25 V	-75	-75		mA
Icc	$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	5.25 V	8	3	80	μΑ
∆ICC§	One input at 3.4 V, Other inputs at V_{CC} or GND	5.25 V	1.6	3	1.6	mA
Ci	$V_I = V_{CC}$ or GND		1()	10	pF
Co	$V_{O} = V_{CC}$ or GND		15	5	15	pF

[‡]Not more than one output should be tested at a time, and the duration of the test should not exceed 100 ms.

§ This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or V_{CC}.



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timing requirements over recommended operating temperature conditions (unless otherwise noted) (see Figure 1)

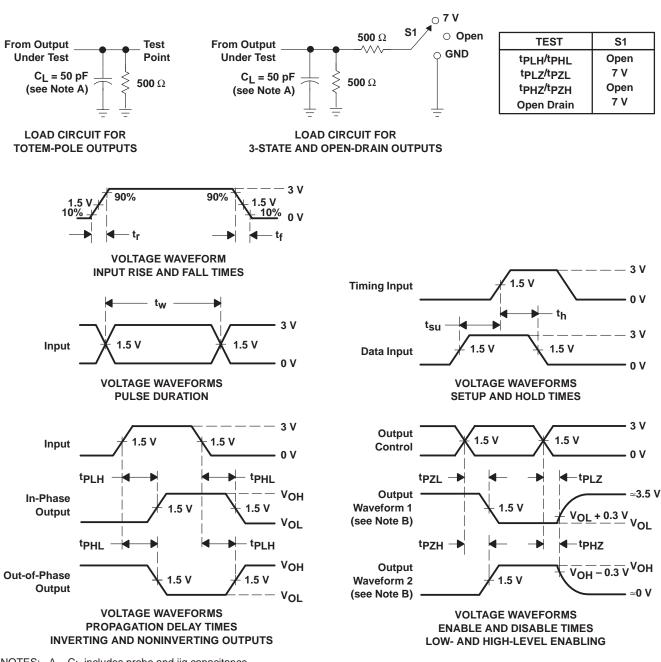
			MIN	MAX	UNIT
		CLR low	8		
t _w Pulse dura	Pulse duration	PRE low	8		ns
		LE low	4		
		Data before LE \downarrow	2.5		
t _{su}	Setup time	PRE inactive	1.4		ns
		CLR inactive	1.4		
t _h	Hold time	Data before LE \downarrow	2.5		ns
t _{rec}	Recovery time	PRE, CLR	14		ns

switching characteristics over recommended operating temperature conditions (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)			MIN	МАХ	UNIT
· .	D	0	6.8	1.5	9	-
^t pd	LE	Q	9	1.5	12	ns
^t PLH	PRE	Q	9	1.5	12	ns
^t PHL	CLR	Q	9.8	1.5	13	ns
ten	OE	Q	10.5	1.5	14	ns
^t dis	OE	Q	6	1.5	8	ns

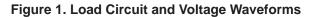


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PARAMETER MEASUREMENT INFORMATION

- NOTES: A. CL includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \le 1$ MHz, $Z_O = 50 \Omega$, t_f and $t_f = 2.5$ ns. D. The outputs are measured one at a time with one input transition per measurement.
 - D. The outputs are measured one at a time
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en}.
 - G. tPHL and tPLH are the same as tpd.







10-Dec-2020

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
CD74FCT843AM	ACTIVE	SOIC	DW	24	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	74FCT843AM	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <= 1000ppm threshold. Antimony trioxide based flame retardants must also meet the <= 1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(⁶⁾ Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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TUBE



*All dimensions are nominal

Device	Package Name Package Type		Pins	SPQ	L (mm)	W (mm)	Τ (μm)	B (mm)
CD74FCT843AM	DW	SOIC	24	25	506.98	12.7	4826	6.6

DW (R-PDSO-G24)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-013 variation AD.



LAND PATTERN DATA



NOTES:

A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Refer to IPC7351 for alternate board design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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